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Application/Control No.	Applicant(s)/Patent under Reexamination
10/643,421	LANEY ET AL.
Examiner	Art Unit

2173

Kieu D. Vu

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Class	Subclass	Date	Examiner
715	867	11/16/2006	ΚV
715	791	11/20/2006	KV
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East search (USPAT USPGPUB EPO JPO DERWENT IBM_TDB USOCR) (See Search History Printout)	11/16/06	KV
text search (See Search History Printout)	11/16/2006	KV
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